#21128 OKO 1271/102

Sheet 1 🚓 🕏

FORM PTO-1449 (Rev. 2-32) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. DP-306551 (DEL01 P-392) SERIAL NO.

INFORMATION DISCLOSURE

STATEMENT BY APPLICANT
(Use several sheets if necessary)

APPLICANTS
S yed R. Zarabadi et al.

FILING DATE

GROUP



### **U.S. PATENT DOCUMENTS**

EXAMINER		DOCUMENT NUMBER				JME	ER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
A	$\sqrt{}$	5	8	4	7	2	8	0	12/08/98	Sherman et al.	73	514	
300	V	5	6	6	5	9	1	5	09/09/97	Kobayashi et al.	73	514	
QN.	J	5	5	7	8	7	5	5	11/26/96	Offenberg	73	514	
QVV	1	5	5	6	9	8	5	2	10/29/96	Marek et al.	73	514	
Syl	<b>V</b>	5	5	4	0	0	9	5	07/30/96	Sherman et al.	73	514	
$\mathcal{A}_{\mathcal{A}}$	$\checkmark$	5	4	1	7	1	1	1	05/23/95	Sherman et al.	73	517	
(MA)	V	5	3	8	8	4	6	0	02/14/95	Sakurai et al.	73	517	
011	$\sqrt{}$	5	3	4	9	8	5	8	09/27/94	Yagi et al.	73	517	
<b>₩</b>	\	5	3	4	5	8	2	4	09/13/94	Sherman et al.	73	517	
	$\checkmark$	5	3	1	4	5	7	2	05/24/94	Core et al.	156	643	
<b>M</b>	<b>/</b>	5	3	1	0	4	5	0	05/10/94	Offenberg et al.	156	630	

## **FOREIGN PATENT DOCUMENTS**

		DO	DOCUMENT NUMBER					ER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
													YES	NO	
W	1	0	5	8	3	3	9	7	12/1977	Russia ,	73	517A	X Abstract		
3/2	1	1	0	3	5	5	2	3	08/1983	Russia	73	517A	X Abstract		
Que la companya de la companya della companya della companya de la companya della		1	0	4	0	4	2	4	09/1983	Russia ,	73	517A	X Abstract		

## OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

O.b.	"Rejecting Rotational Disturbances on Small Disk Drives Using Rotational Accelerometers" Daniel Y. Abramovitch, 1996, IFAC World Congress in San Francisco, CA 1996, pp. 1-6.
	"Increased Disturbance Rejection in Magnetic Disk Drives by Acceleration Feedforward Control and Parameter Adaption" M.T. White and M. Tomizuka, Vol. 5, No. 6, 1997, pp. 741-751.
	"Surface-Micromachined-Angular-Accelerometer-with-Force Peedback" T.J. Brosnihan, A.P. Pisano and R.T. Howe, DSG=Voi::57-2, 1995, IMECE-pp:-941-947.
	, "Embedded-Interconnect and Electrical-Isolation-for-High-Aspect-Ratio, SOI Inertial Instruments" T.J. Brosninan, J.M. Bustillo, A.P. Pisano and R.T. Howe, 1997. International Conference on Solid-State Sensors and Actuators, Chicago, June, 16-19-1997, pp637-640.

EXAMINE

DATE CONSIDERED

6/20/03

EXAMINER Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Form PTO-1449 [6-4])

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE	ATTY. DOCKET NO.	SERIAL NO.				
(Rev. 2-32)	PATENT AND TRADEMARK OFFICE	DP-306551 (DEL01 P-392)					
		APPLICANTS					
	INFORMATION DISCLOSURE	Seyed R. Zarabadi et al.					
	STATEMENT BY APPLICANT	FILING DATE	GROUP				
	(Use several sheets if necessary)	<u></u>					

## **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER						BER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
O xe	$\sqrt{}$	5	2	5	3	5	2	6	10/19/93	Omura et al.	73	517	
QV.	/	5	2	5	1	4	8	4	10/12/93	Mastache	73	517	
A.F.	✓.	5	2	4	9	4	6	5	10/05/93	Bennett et al.	73	510	
Q Jo	$\overline{\ }$	5	2	3	3	2	1	3	08/03/93	Marek	257	415	<u> </u>
QD	\	5	2	2	6	3	2	1	07/13/93	Varnham et al.	73	505	
QN	V	5	1	4	6	3	8	9	09/08/92	Ristic et al.	361	283	
Q1	V	5	0	9	2	1	7	4	03/03/92	Reidemeister et al.	73	517	
$\propto$	J	4	8	5	1	0	8	0	07/25/89	Howe et al.	156	647	
AM	J	4	8	0	5	4	5	6	02/21/89	Howe et al.	73	517	
ONTA	>	4	7	3	6	6	2	9	04/12/88	Cole	73	517	
CON C	V'	4	6	9	9	0	0	6	10/13/87	Boxenhorn	73	517	
7				-	-	-	-						

## **FOREIGN PATENT DOCUMENTS**

DOCUMENT NUMBER							ER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
												YES	NO	
												·		

# OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

-			
EXAMINE		Y.	DATE CONSIDERED 6/20/03
	7	1	

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Form PTO-1449 [6-4])

C)	20	4	2	of	1
OI	16	еı	J	OI.	-

FOR					U.S	S. DE	PARTMEN	T OF COMMERCE	ATTY. DOCKET N	10.	S	SERIA	L NO.				
(Rev	. 2-32)							PA.	TEN	IT AND TRA	DEMARK OFFICE	DP-306551 (DEL0	1 P-392)				
												APPLICANTS					
								INF	OR	MATION DI	SCLOSURE	Seyed R. Zarabad	i et al.				
								STA	ATE	MENT BY A	APPLICANT	FILING DATE		0	SROU	P	
								(Us	e se	everal sheet	s if necessary)						
						_				U	.S. PATENT DOC	CUMENTS		-			
EX	AMINER																G DATE
Ш	NITIAL		DO	oci	JME	ENT	N	JME	BER	DATE	N/	AME	CLASS	SUBCL	ASS	IF APPE	ROPRIATE
$\overline{\mathcal{N}}$	$\Lambda$		4	4	3	5	7	3	7	03/06/84	Colton		361	280			
W	1,4		2	9	+-	6	2	7	9	12/08/59	Stanton		264	1			
To a	<u> </u>	<del>                                     </del>	2	9	-	2	6	5	7	11/10/59	Schaevitz		336	30			
1	<u>~~</u>	$t^-$	1	T	t	Ť	t	T	T	<del>                                     </del>		·	†			-	
		╁	╁	┢	╁	╁╌	╁╴	+	╁								
		╁	┿	┝	╁	╁╌	╁╴	╁	╁					<del> </del>			
		╀	╀	┝	╁	╀	╀	╀	╆		<u> </u>	<del></del>		<b>-</b>			
		_	╄	_	╄	╀	╀		-	ļ			+		-		
		_	<u> </u>		L	L	$\perp$	1_	<u> </u>								
				L			L	<u> </u>	L	<u> </u>							
	-																
				Г	Γ	Г	Т										
		<b>-</b>	1							FOR	EIGN PATENT D	OCUMENTS	ΤΤ	-	<del></del>	TDANS	LATION
			Do	ocu	JME	ENT	· NU	JME	BER	DATE	COUN	ITRY CLASS SUBG			TRANSLATIO		
																YES	NO
				Π	Ţ		Τ	Τ	Т								
					Ι												
							L										
													<u>1 1 1 </u>		$\bot$		
				ОТ	HE	ER	DC	CI	UM	ENTS (in	cluding Author,	Title, Date, Pert	inent P	ages, E	tc.)		
-			L	L													
		<u> </u>	_	$\bot$											_		
			$\vdash$	$\perp$													
		├-	+	╀													
			$\vdash$	+			_								<u></u>		
		Ц															
E	XAMINE	ER(		£.	٨		J.	F	W	<u>ل</u>	DA	TE CONSIDER	ED &	120	,/c	23	

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Form PTO-1449 [6-4])